



SHEET 1 OF 1

<b>LIST OF ART CITED BY APPLICANT</b> <b>(PTO-1449)</b>				ATTY. DOCKET NO. <b>LT-0034</b>		APPLN. SERIAL NO. <b>10/743,303</b>	
				APPLICANT(S) <b>Cheul Kyung HAN</b>			
				FILING DATE <b>December 23, 2003</b>		GROUP <b>2627</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS		
<b>U.S. PATENT APPLICATIONS</b>							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/JH/	JP 2001-067669	03/16/2001	Japan (Japanese Full Text and English Abstract)			X	
/JH/	CN 1276597	12/13/2000	China (Chinese Full Text and English Abstract)			X	
/JH/	EP 1 174 862	06/19/2001	Europe			X	
/JH/	EP 1 211 678	11/29/2001	Europe			X	
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)</b>							
Korean Office Action dated November 19, 2004.							
Chinese Office Action dated July 22, 2005 and its English translation.							
European Search Report dated February 20, 2007.							
EXAMINER				DATE CONSIDERED			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.  
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U.S. PATENT APPLICATIONS							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/JH/	JP 2001-344752	12/14/2001	Japan (Japanese Full Text and English Abstract)			X	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)							
Japanese Official Action dated June 20, 2007.							
EXAMINER /Joseph Haley/				DATE CONSIDERED 11/01/2007			

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